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PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Docket No: Q67625

SMILANSKY, Zeev, et al.

Appln. No.: 10/003,347



Group Art Unit: 2623

Confirmation No.: 6579

Examiner: Vikkram Bali

Filed: December 06, 2001

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For: A PIXEL BASED MACHINE FOR PATTERNED WAFERS

RESPONSE TO RESTRICTION REQUIREMENT

Commissioner for Patents
Washington, D.C. 20231

Sir:

This is in response to the Office Action dated July 15, 2002, which issued a restriction requirement under 35 U.S.C. § 121. The Examiner requests that Applicant select one of the following groups for prosecution on the merits:

Group I - Claims 1-4, drawn to defect detection using pixel signatures, classified in class 382, subclass 149

Group II - Claims 5-7, drawn to pattern analysis with coordinate transformation, classified in class 382, subclass 276

Group III - Claims 15, drawn to defect detection using the decay rate, classified in class 382, subclass 147.

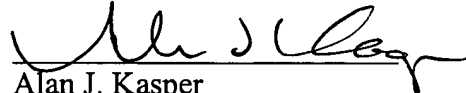
Applicants elect the claims of Group I for examination. The election is without traverse and without prejudice to the filing of one or more divisional applications on the non-elected claims.

In view of the above, reconsideration and allowance of this application are now believed to be in order, and such actions are hereby solicited. If any points remain in issue which the Examiner feels may be best resolved through a personal or telephone interview, the Examiner is kindly requested to contact the undersigned at the telephone number listed below.

The USPTO is directed and authorized to charge all required fees, except for the Issue Fee and the Publication Fee, to Deposit Account No. 19-4880. Please also credit any overpayments to said Deposit Account.

Respectfully submitted,

SUGHRUE MION, PLLC
2100 Pennsylvania Avenue, N.W.
Washington, D.C. 20037-3213
Telephone: (202) 293-7060
Facsimile: (202) 293-7860


Alan J. Kasper
Registration No. 25,426

Date: September 19, 2002